Silicon P Channel MOS FET High Speed Power Switching

HITACHI

ADE-208-580B (Z) 3rd. Edition June 1, 1998

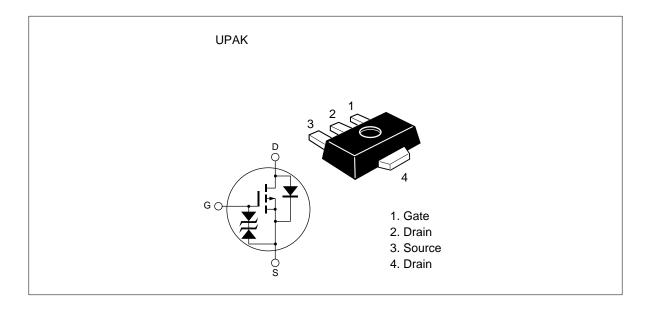
Features

Low on-resistance

$$R_{\mathrm{DS(on)}} = 0.35~\Omega$$
 typ. at $(V_{\mathrm{GS}} = -10\mathrm{V}, I_{\mathrm{D}} = -1\mathrm{A})$

- Low drive current
- 4 V gate drive devices
- High speed switching

Outline



Absolute Maximum Ratings $(Ta = 25^{\circ}C)$

Item	Symbol	Ratings	Unit
Drain to source voltage	$V_{ exttt{DSS}}$	-60	V
Gate to source voltage	$V_{\rm GSS}$	±20	V
Drain current	I _D	-2	A
Drain peak current	Note1	-4	A
Body-drain diode reverse drain current	I _{DR}	-2	A
Avalanche current	Note2	-2	A
Avalanche energy	E _{AR}	0.34	mJ
Channel dissipation	Pch Note3	1	W
Channel temperature	Tch	150	°C
Storage temperature	Tstg	-55 to +150	°C

Note: 1. PW \leq 10 μ s, duty cycle \leq 1 %

- 2. value at Tch = 25°C, Rg \geq 50 Ω
- 3. Value at when using the aluminaceramic board (12.5x20x0.7mm)

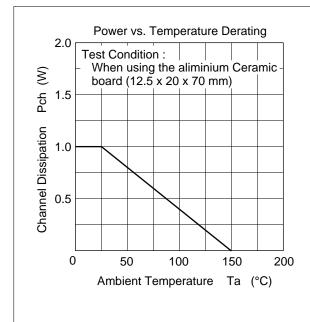
Electrical Characteristics (Ta = 25°C)

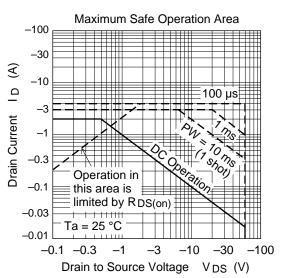
Item	Symbol	Min	Тур	Max	Unit	Test Conditions
Drain to source breakdown voltage	$V_{(BR)DSS}$	-60	_	_	V	$I_D = -10 \text{mA}, V_{GS} = 0$
Gate to source breakdown voltage	$V_{(BR)GSS}$	±20	_	_	V	$I_{G} = \pm 100 \mu A, V_{DS} = 0$
Zero gate voltege drain current	I _{DSS}	_	_	-10	μΑ	$V_{DS} = -60 \text{ V}, V_{GS} = 0$
Gate to source leak current	I _{GSS}	_	_	±10	μΑ	$V_{GS} = \pm 16V, V_{DS} = 0$
Gate to source cutoff voltage	$V_{\text{GS(off)}}$	-1.0	_	-2.0	V	$I_{D} = -1 \text{mA}, \ V_{DS} = -10 \text{V}$
Static drain to source on state	R _{DS(on)}	_	0.35	0.46	Ω	$I_{\rm D} = -1A, V_{\rm GS} = -10V^{\rm Note4}$
resistance	R _{DS(on)}	_	0.45	0.63	Ω	$I_D = -1A$, $V_{GS} = -4V$ Note4
Forward transfer admittance	y _{fs}	1.2	2.0	_	S	$I_{D} = -1A, V_{DS} = -10V^{Note4}$
Input capacitance	Ciss	_	220	_	pF	$V_{DS} = -10V$
Output capacitance	Coss	_	110		pF	V _{GS} = 0
Reverse transfer capacitance	Crss	_	35	_	pF	f = 1MHz
Turn-on delay time	t _{d(on)}	_	10	_	ns	$V_{GS} = -10V, I_{D} = -1A$
Rise time	t _r	_	11	_	ns	$R_L = 30\Omega$
Turn-off delay time	t _{d(off)}	_	45	_	ns	
Fall time	t _f	_	30	_	ns	
Body-drain diode forward voltage	V_{DF}	_	-1.05	_	V	$I_{D} = -2A, V_{GS} = 0$
Body-drain diode reverse recovery time	t _{rr}	_	50		ns	$I_F = -2A, V_{GS} = 0$ diF/ dt = 50A/ μ s

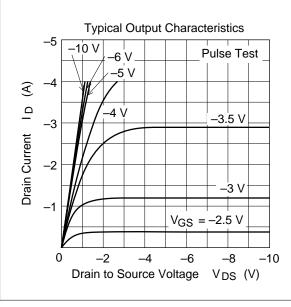
Note: 4. Pulse test

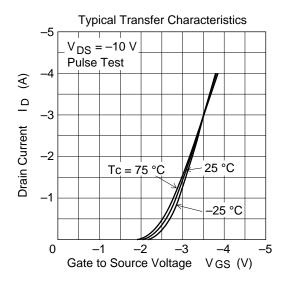
5. Marking is "AZ"

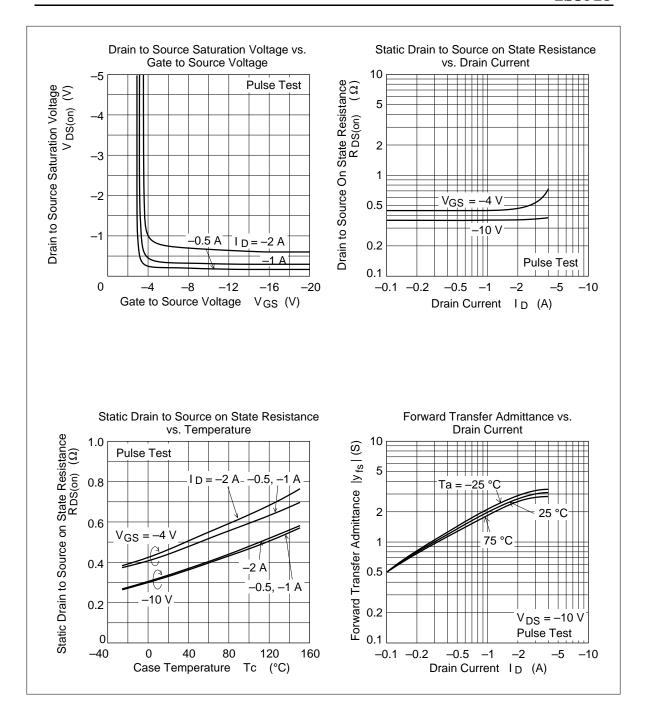
Main Characteristics

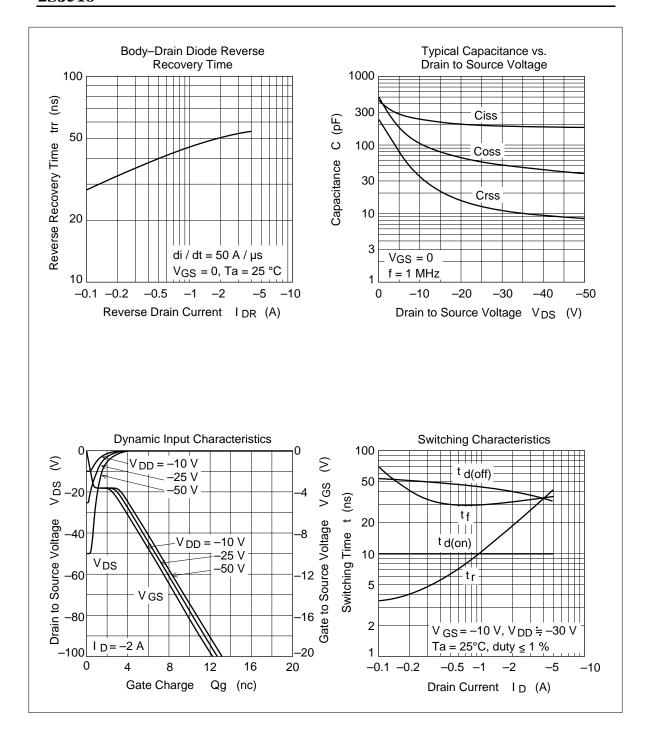


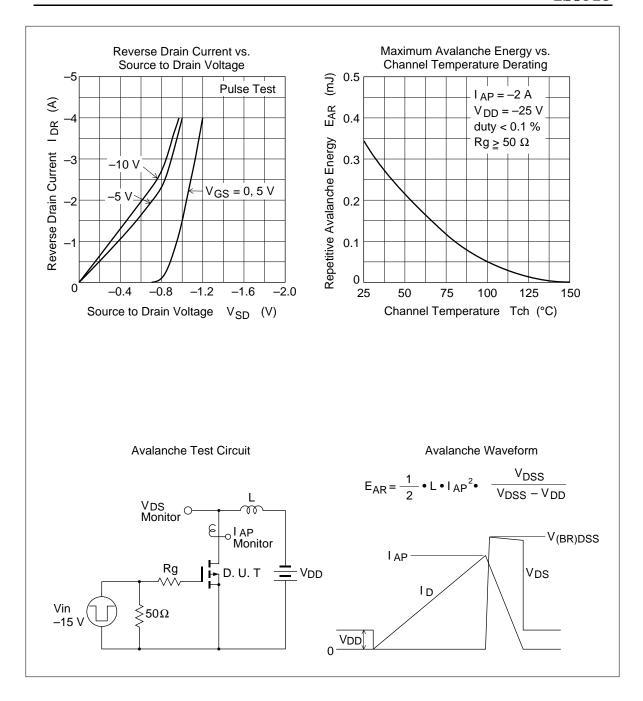


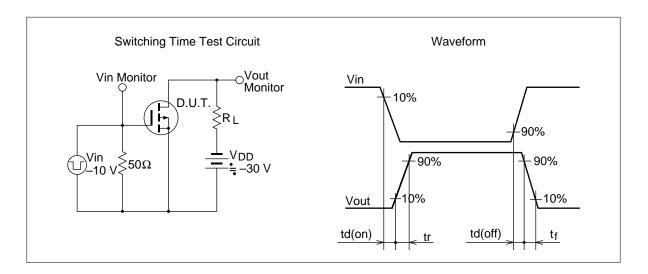




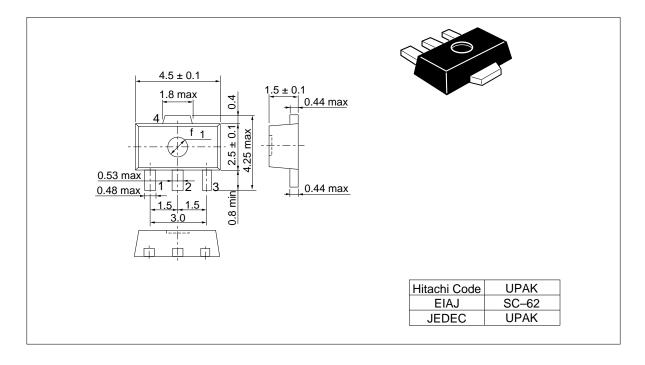








Package Dimensions (Unit: mm)



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